## Notice of References Cited

Application/Control No.

O9/852,563

Examiner

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Applicant(s)/Patent Under
Reexamination
UCHIO ET AL.

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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,159,180	10-1992	Feiler, William S.	235/375
*	В	US-5,175,681	12-1992	Iwai et al.	705/9
*	С	US-5,329,447	07-1994	Leedom, Jr., Charles M.	705/9
*	D	US-5,557,515	09-1996	Abbruzzese et al.	705/9
*	E	US-5,721,910	02-1998	Unger et al.	707/100
*	F	US-5,875,431	02-1999	Heckman et al.	705/7
*	G	US-6,098,070	08-2000	Maxwell, John M.	707/102
*	Н	US-6,119,097	09-2000	Ibarra, David	705/11
*	1	US-6,366,925	08-2002	Meltzer et al.	705/6
*	J	US-6,430,581	08-2002	Mahoney et al.	715/500
*	·K	US-6,499,026	12-2002	Rivette et al.	707/2
*	Ľ	US-6,549,894	04-2003	Simpson et al.	707/1
*	М	US-6,789,092	09-2004	Oppedahl et al.	707/104.1

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
4	R			•		
	s	•				
	Т	,				

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	<b>v</b>	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.